Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/002,722	CHEN ET AL.	
Examiner	Art Unit	_
Ted M. Wang	2611	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	7/21/2006	TW
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